

**Search Notes**

Application/Control No.

10/674,338

Examiner

Ellen Kim

Applicant(s)/Patent under  
Reexamination

HAYAMI ET AL.

Art Unit

2874

**SEARCHED**

| Class | Subclass | Date       | Examiner |
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| 385   | 137-138  | 10/28/2005 | EK       |
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**INTERFERENCE SEARCHED**

| Class | Subclass | Date       | Examiner |
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| 385   | 137-138  | 10/28/2005 | EK       |
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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|      | DATE       | EXMR |
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